PCN-275184

Product Change Notice

Issue Date: 24-January-2024

Change Description:
New Wafer Sort Test Floor (K27) at ASE-KH

Parts Affected:

BCM89252YD0BFBG	BCM89557YD0BFBG
BCM89259YD0BFBG	BCM89557YD0BFBGT
BCM89259YD0BFBGT	BCM89559YD0BFBG
BCM89549YD0BFBG	BCM89559YD0BFBGT
BCM89553YD0BFBG	

Description and Extent of Change:
Electrical wafer sort testing is currently performed on this product at ASE-KH (Kaohsiung City, Taiwan R.O.C.). ASE-KH is expanding wafer sort capacity to a new test floor – K27. There will be **no change** to the:

- QMS System
- Wafer Sort Flow
- Environmental Controls
- Control Plan
- Testers / Test Hardware / Test Software

There is no change to Foundry, Assembly or Final Test for this PCN.

Reasons for Change:
Increase wafer sort capacity

Effect of Change on Fit, Form, Function, Quality, or Reliability:
The device specification, test limits, SYA/SBL limits, and D-PAT will remain the same, which will ensure product electrical performance remains the same. Appropriate correlation has been performed to ensure no impact on Fit, Form, Function, Quality, or Reliability. In addition, the devices are fully tested at Hot and Cold temperature at Final Test.

Effective Date of Change:
Product shipments using this change will begin after **31-Jul-2024**. Timing of shipment of parts tested at ASE-KH (K27) will vary by part number depending on customer demand and inventory levels.

Correlation Information:
The correlation activity has successfully completed. See the table below for details.

Note: All of the part numbers listed in this PCN use the same chip design and wafer sort test program.

Correlation Item	ASE-KH (K27) Result	OK/NOK
Tester	Same as at existing test floor	OK
Test DIB and probe card	Same as at existing test floor	OK
Test Program	Same as at existing test floor	OK
Test time / # of tests	Same as at existing test floor	OK
SYA/SBL limits	Same as at existing test floor	OK
D-PAT limits	Same as at existing test floor	OK
Loop 50 times; 5 units/site @ Room Temp	1500/1500 pass	OK
Run 1 correlation wafer (yield/reject comparison)	Pass	OK
Analog test parameter correlation	Pass	OK

Please contact your Broadcom field sales engineer or Contact Center for any questions or support requirements. Please return any response as soon as possible, but **not to exceed 30 days**.